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Problem Description

Power grids

- used to distribute power to feed all electrical devices within an integrated circuit
- may suffer from voltage drop, ground bounce, Ldi/dt noise and electromigration

Power Grid Analysis

- excessive cell switching activity in a given region may cause voltage droop affecting performance
- worst-case scenario is hard to determine
- size (millions of nodes) complicate its verification

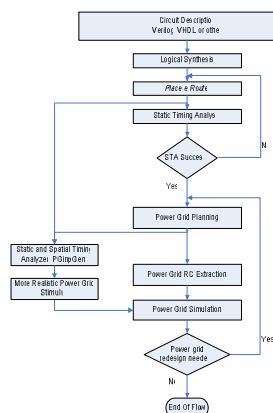
Objectives

- find a realistic set of stimuli that helps predicting worst-case scenario
- search for regions with a high concentration of cell activity that may cause grid integrity problems

Proposed Approach

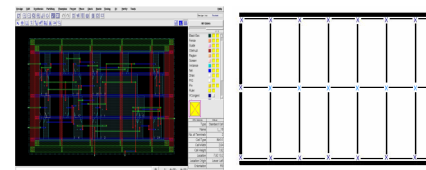
Combines information from

- timing correlations between cells
- circuit placement & routing
- power grid structure



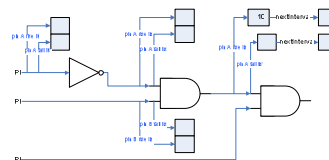
Methodology

1 Power Grid discretization



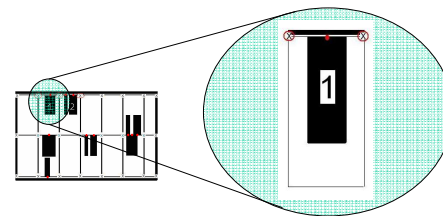
2 Timing correlations

- obtained by traversing the circuit
- uses intervals instead of single instants of time



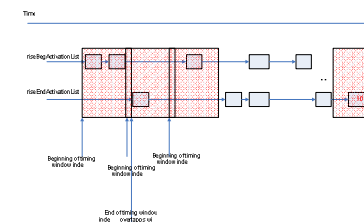
3 Spatial information

- obtained from placement
- connections between each cell and the power grid
- proximity between cells

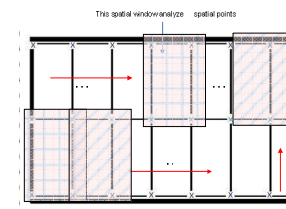


4 Combine all info & search the power grid

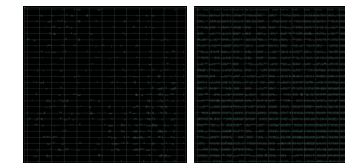
- Determine the time interval where the largest number of switching cells occurs



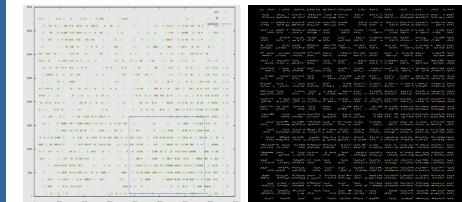
- For each time interval determine which region of the power grid is the most affected



Integration of PGinGen with Voltage Storm



Using PGinGen to detect hot-spots



Conclusions

- Only a small fraction of blocks can switch in a given time interval
- PGinGen:
 - runs almost as fast as regular STA
 - less pessimistic than other methodologies
 - can be integrated with power grid analysis tools
 - enables faster power grid analysis by zooming in on the most troublesome regions
- Additional uses of PGinGen in the design cycle:
 - quickly detect hot-spots

Acknowledgements

This work was partly supported by Project POSI/EEA-ESE/61528/2004- PowerPlan – Planeamento de Potência em Sistemas Electrónicos

Experimental Results

PGinGen implements the proposed methodology

Circuit Name	s27	s1196	s5378	s13207	s35932	s38417	s38584
# of gates	23	945	2680	6084	24732	20872	27150
Active cells (t.w. 0.1 ns)	43%	7%	8%	10%	18%	22%	15%
STA run-time (s)	0.15	0.70	2.47	14.83	139.59	77.19	68.17
PGinGen run-time (s)	0.16	0.87	3.08	16.37	142.33	82.02	73.9